PERFORMANCE CHECKSHEET

Model: AVR-EB2A-B-R5-SOT23B-2YW
Type: Semiconductor Device Tester
S.N.: 13264
Date: February 19, 2015

Basic specifications:
- Output Amplitude: to +100 mA, -100 mA
- Pulse Width (FWHM): 200 ns
- Switching Time, + to -, 10%-90%: ≤ 300 ps (at mainframe)
- PRF: 1 - 10 kHz
- Jitter, Stability: OK
- Prime Power: 100-240V AC, 50-60 Hz.

Test Waveforms

With a Fairchild MMBD4148CC installed in the AVX-CA-SOT23B test jig, with pin 1 = anode, pin 3 = cathode, pin 2 = unused. 40 mA/div, 2 ns/div.

![Waveform 1](image1)

$I_F = +100$ mA, $I_R = -100$ mA, $I_{RR} = -10$ mA,

Measured $t_{RR} = 5.8$ ns.

With a Fairchild MMBD4148CC installed in the AVX-CA-SOT23B test jig, with pin 2 = anode, pin 3 = cathode, pin 1 = unused. 4 mA/div, 2 ns/div.

![Waveform 2](image2)

$I_F = +10$ mA, $I_R = -10$ mA, $I_{RR} = -1$ mA,

Measured $t_{RR} = 3.4$ ns.
Pulse output directly from mainframe, with the test jig bypassed (2 V/div, 1 ns/div):

Shows a 10%-90% transition time of 185 ps.